

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/786,811	ZHENG ET AL.	
		Examiner	Art Unit	Page 1 of 1
		Dawn Garrett	1774	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0108807	06-2004	Park, Byoung Choo	313/504
*	B	US-6,803,124	10-2004	Taguchi, Toshiki	428/690
*	C	US-2002/0027623	03-2002	Doi et al.	349/69
*	D	US-6,821,649	11-2004	Kambe et al.	428/690
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Peng et al., Chemtech, 29(5), p. 41-46, 1999.
	V	Lee et al., Chem. Materials, 2001, 13, p. 565-574.
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.